# imall

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## **Diode EMCON 4 Medium Power Chip**

### FEATURES:

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1200V EMCON 4 technology •

small temperature coefficient

soft, fast switching • low reverse recovery charge

### This chip is used for:

low / medium power modules •



### **Applications:**

low / medium power drives •

Chip Type	VR	I <sub>F</sub>	Die Size	Package
IDC08D120T6M	1200V	10A	2.20 x 3.41 mm <sup>2</sup>	sawn on foil

## **MECHANICAL PARAMETER:**

Raster size	2.20 x 3.41				
Area total / active	7.50 / 3.55	mm <sup>2</sup>			
Anode pad size	1.246 x 2.456	1			
Thickness	110	μm			
Wafer size	150	mm			
Flat position	180	deg			
Max. possible chips per wafer	2024 pcs				
Passivation frontside	Photoimide				
Pad metall	3200 nm AlSiCu				
Backside metall	Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500µm				
Reject ink dot size	Ø 0.65mm; max 1.2mm				
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



## **Maximum Ratings**

Parameter	Symbol	Condition	Value	Unit		
Repetitive peak reverse voltage	V <sub>RRM</sub>		1200	V		
Continuous forward current limited by T <sub>jmax</sub>	I <sub>F</sub>		1)	A		
Maximum repetitive forward current limited by T <sub>jmax</sub>	I <sub>FRM</sub>		20			
Maximum junction and storage temperature	T <sub>vj,max</sub> , T <sub>stg</sub>		-40+175	°C		
Reverse bias safe operating area <sup>2)</sup> (RBSOA)	$I_{F,max} = 20A, V_{R,max} = 1200V, T_{vj,op} \le 150^{\circ}C, P_{max} = $ tbd kW					

<sup>1)</sup> depending on thermal properties of assembly

<sup>2)</sup> not subject to production test - verified by design/characterisation

Parameter	Symbol	Condi	Value			Unit	
	Gymbol	Cond	min. Typ. max.		max.		
Reverse leakage current	/ <sub>R</sub>	V <sub>R</sub> =1200V	$T_j=25^\circ C$			2.7	μA
Cathode-Anode breakdown Voltage	V <sub>Br</sub>	I <sub>R</sub> =0.25mA	<i>T<sub>j</sub>=25°C</i>	1200			V
Forward voltage drop	V <sub>F</sub>	I <sub>F</sub> = 10A	$T_j=25^\circ C$	1.35	1.7	2.05	V

## Static Electrical Characteristics (tested on wafer), $T_i=25$ °C

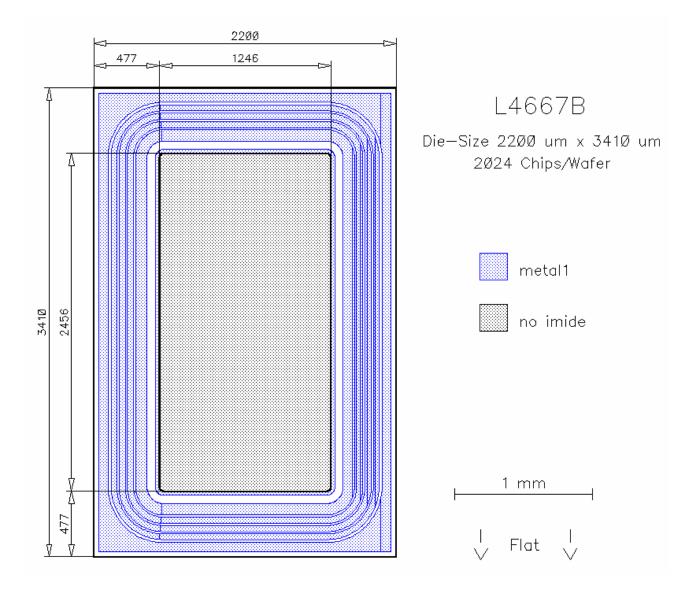
## **Dynamic Electrical Characteristics** inductive load (not subject to production test - verified by design/characterization)

Parameter	Symbol	Conditions		Value <sup>2)</sup>			Unit
Falametei	Symbol			min.	Тур.	max.	
Peak reverse recovery current	I <sub>RM</sub>	$I_{F}=A$ $di/dt=A/\mu s$ $V_{R}=V$ $V_{GE}=-15V$	$T_{j} = 25 \ ^{\circ}C$ $T_{j} = 125 \ ^{\circ}C$ $T_{j} = 150 \ ^{\circ}C$		tbd		А
Reverse recovery charge	Q <sub>r</sub>	$I_{F}=A$ $di/dt=A/\mu s$ $V_{R}=V$ $V_{GE}=-15V$	$T_{j} = 25 \ ^{\circ}C$ $T_{j} = 125 \ ^{\circ}C$ $T_{j} = 150 \ ^{\circ}C$		tbd		μC
Reverse recovery energy	E <sub>rec</sub>	$I_{F}=A$ $di/dt=A/\mu s$ $V_{R}=V$ $V_{GE}=-15V$	$T_j = 25 \ ^{\circ}C$ $T_j = 125 \ ^{\circ}C$ $T_j = 150 \ ^{\circ}C$		tbd		mJ

<sup>2)</sup> values also influenced by parasitic L- and C- in measurement and package.



### **CHIP DRAWING:**





### FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

tbd

### Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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